Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
09/747,004	HU ET AL.	
Examiner	Art Unit	_
Young J. Kim	1637	

SEARCHED					
Class	Subclass	Date	Examiner		
			-		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
			-	
	·			

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Patent Database (USPT, USPGP, EPO, JPO, DERWENT, IBM-TDB) search updated	2/19/2006	YJK		
· · · · · · · · · · · · · · · · · · ·				